

**INFORMATION DISCLOSURE
STATEMENT BY APPLICANT**

(Substitute for form 1449/PTO)

ATTY. DOCKET NO.
044117-0143SERIAL NO.
10/539,771APPLICANT
Eric PINET, et al.FILING DATE
January 10, 2006GROUP
1797**U.S. PATENT DOCUMENTS**

EXAMINER'S INITIALS	CITE NO.	Document Number Number-Kind Codes (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
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OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)

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